

Search Notes



Application/Control No.

10/757,115

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

SMITH ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
^{EAST} See abstract	05-16-06	Hn

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner